



CAS300M12BM2 1.2kV, 5.0 mΩ All-Silicon Carbide Half-Bridge Module

Z-FET™ MOSFET and Z-Rec™ Diode

V_{DS}	= 1.2 kV
$E_{sw,Total@300A}$	= 12.0 mJ
$R_{DS(on)}$	= 5.0 mΩ

Module Features

- Ultra Low Loss
- High-Frequency Operation
- Zero Reverse Recovery Current from Diode
- Zero Turn-off Tail Current from MOSFET
- Normally-off, fail-safe device operation
- Ease of paralleling
- Copper baseplate and aluminum nitride insulator

System Benefits

- Enables compact and lightweight systems
- High efficiency operation
- Mitigates over-voltage protection
- Reduces thermal requirements
- Enables simplified topologies

Applications

- Induction Heating
- Motor Drives
- Solar and Wind Inverters
- UPS and SMPS
- Traction

Package 62 mm x 106 mm x 30 mm



Part Number	Package	Marking
CAS300M12BM2	Half Bridge Module	CAS300M12BM2

Maximum Ratings ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V_{DSmax}	Drain – Source Voltage	1.2	kV		
V_{GSmax}	Gate – Source Voltage	-10/+25	V	Absolute maximum values	
V_{GSop}	Gate – Source Voltage	-5/+20	V	Recommended operational values	
I_D	Continuous Drain Current	404	A	$V_{GS} = 20\text{ V}$, $T_C = 25^\circ\text{C}$	Fig 20
		285	A	$V_{GS} = 20\text{ V}$, $T_C = 90^\circ\text{C}$	
I_{Dpulse}	Pulsed Drain Current	1500	A	Pulse width $t_P = 200\text{ }\mu\text{s}$ repetition rate limited by $T_{J(max)}$, $T_C = 25^\circ\text{C}$	
T_{Jmax}	Junction Temperature	150	$^\circ\text{C}$		
T_C T_{stg}	Case and Storage Temperature Range	-40 to +125	$^\circ\text{C}$		
P_{tot}	Maximum Power Dissipation	1660	W	$T_C = 25^\circ\text{C}$, $T_J = 150^\circ\text{C}$	
V_{isol}	Case Isolation Voltage	4.0	kV	AC, 50 Hz, 1 min	
L_{stray}	Stray Inductance	14	nH	Measured between terminals 2 and 3	
M	Mounting Torque	5	Nm	To heatsink and terminals	
G	Weight	300	g		
	Clearance Distance	12	mm	Terminal to terminal	
	Creepage Distance	30	mm	Terminal to terminal	
		40	mm	Terminal to baseplate	



Electrical Characteristics (T_C = 25°C unless otherwise specified)

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
V _{(BR)DSS}	Drain – Source Breakdown Voltage	1.2			kV	V _{GS} = 0 V, I _{DS} = 1 mA	
V _{GS(th)}	Gate Threshold Voltage	2.0	2.3		V	V _{DS} = 10 V, I _{DS} = 15 mA	Fig 11
I _{DSS}	Zero Gate Voltage Drain Current		500	2000	μA	V _{DS} = 1.2 kV, V _{GS} = 0 V	
			1000			V _{DS} = 1.2 kV, V _{GS} = 0 V T _J = 150 °C	
I _{GSS}	Gate-Source Leakage Current		1	100	nA	V _{GS} = 20 V, V _{DS} = 0 V	
R _{DS(on)}	Drain-Source On-State Resistance		5.0	5.7	mΩ	V _{GS} = 20 V, I _{DS} = 300 A	Fig 4, 5 and 6
			8.6	9.8		V _{GS} = 20 V, I _{DS} = 300 A, T _J = 150 °C	
g _{fs}	Transconductance		94.8		S	V _{DS} = 20 V, I _{DS} = 300 A	Fig 7
			93.3			V _{DS} = 20 V, I _{DS} = 300 A, T _J = 150 °C	
C _{ISS}	Input Capacitance		11.7		nF	V _{DS} = 600 V f = 200 kHz, V _{AC} = 25 mV	Fig 17, 18
C _{OSS}	Output Capacitance		2.55				
C _{RSS}	Reverse Transfer Capacitance		0.07				
t _{d(on)}	Turn-On Delay Time		76			V _{DD} = 600 V, V _{GS} = -5/20 V I _D = 300 A, R _{G(ext)} = 2.5 Ω, Timing relative to V _{DS} Per IEC60747-8-4 pg 83 Inductive Load	Fig 24
t _r	Rise Time		68				
t _{d(off)}	Turn-Off Delay Time		168				
t _f	Fall Time		43				
E _{ON}	Turn-On Switching Energy		6.05		mJ	V _{DS} = 600 V, V _{GS} = -5 / 20 V I _{DS} = 300 A, R _G = 2.5 Ω, Inductive Load	Fig 25
E _{OFF}	Turn-Off Switching Energy		5.95				

Free-Wheeling Diode Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
V _{SD}	Diode Forward Voltage		1.7	2.0	V	I _{SD} = 300 A, T _J = 25°C, V _{GS} = 0 V	Fig 8, 9 and 10
Q _C	Total Capacitive Charge		2.2	2.5	V	I _{SD} = 300 A, T _J = 150°C, V _{GS} = 0 V	
			3.2		μC		

Note: The reverse recovery is purely capacitive.

Gate Charge Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
Q _{GS}	Gate to Source Charge		166		nC	V _{DS} = 800 V, V _{GS} = -5 /+ 20 V I _{DS} = 300 Amps Per JEDEC24 pg 27	Fig 12
Q _{GD}	Gate to Drain Charge		475				
Q _G	Total Gate Charge		1025				
R _G	Internal Gate Resistance		3.0		Ω	f = 200 kHz, V _{AC} = 25 mV	

Thermal Characteristics

Symbol	Parameter	Value			Unit	Test Conditions	Notes
		Min	Typ	Max			
R _{θJCM}	Thermal Resistance Junction to Case for MOSFET		0.070	0.075	°C/W	T _C = 90 °C, T _J = 150 °C P _{dis} = P _{max}	Fig 17
R _{θJCD}	Thermal Resistance Junction to Case for Diode		0.073	0.076			Fig 18

Typical Performance

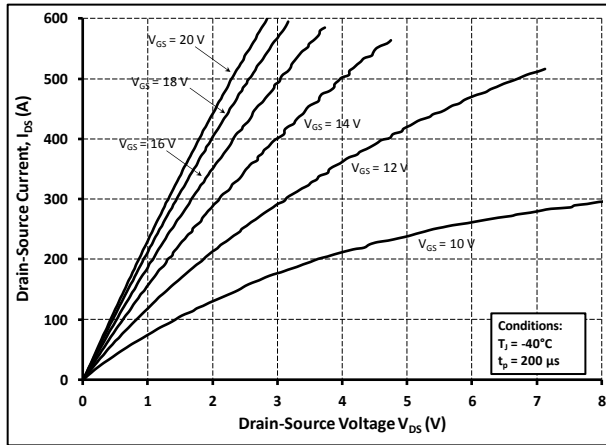


Fig 1. Typical Output Characteristics $T_J = -40\text{ }^{\circ}\text{C}$

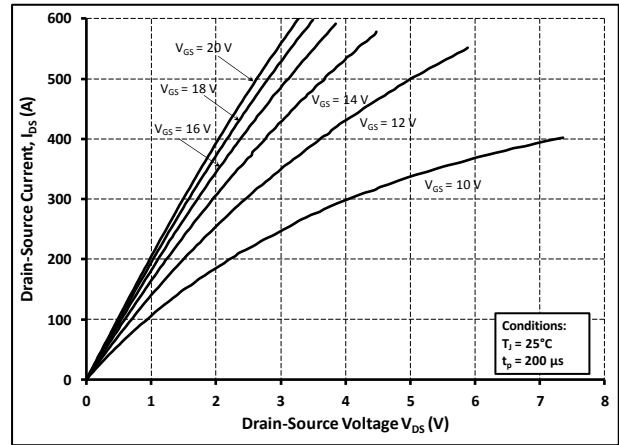


Fig 2. Typical Output Characteristics $T_J = 25\text{ }^{\circ}\text{C}$

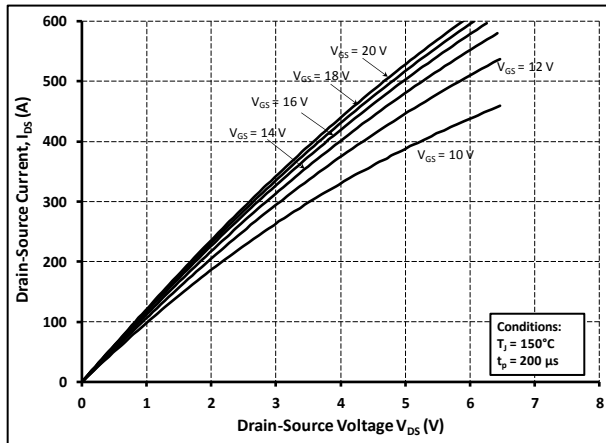


Fig 3. Typical Output Characteristics $T_J = 150\text{ }^{\circ}\text{C}$

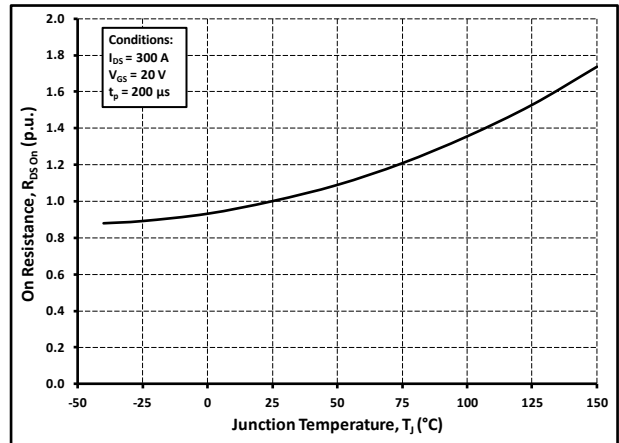


Fig 4. Normalized On-Resistance vs. Temperature

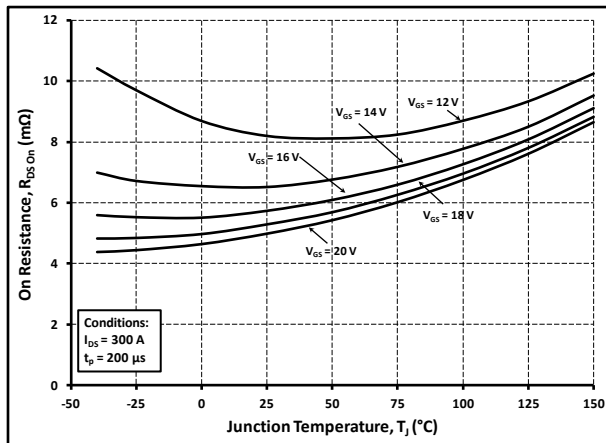


Fig 5. Typical On-Resistance vs. Temperature and Gate Voltage

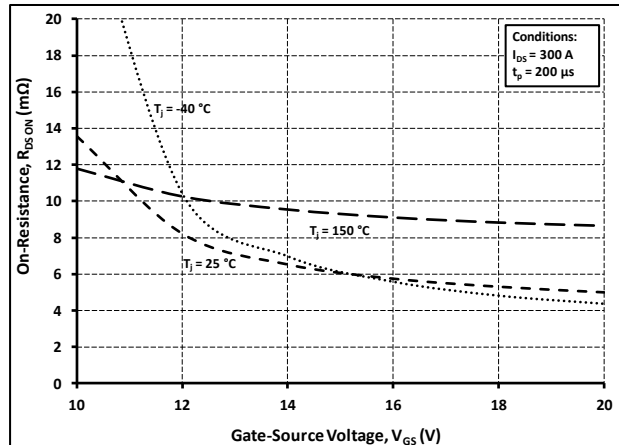


Fig 6. Typical On-Resistance vs. Gate Voltage

Typical Performance

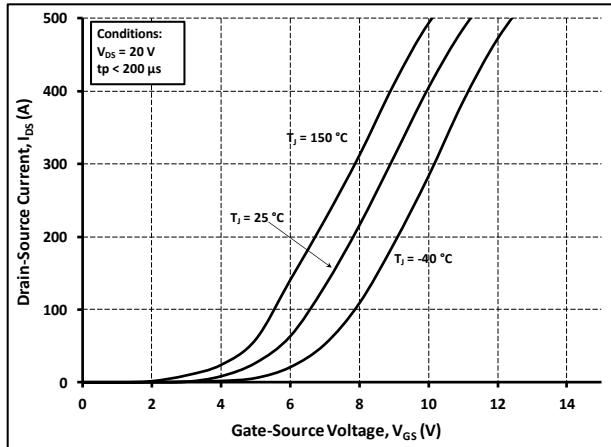


Fig 7. Typical Transfer Characteristic For Various Temperatures

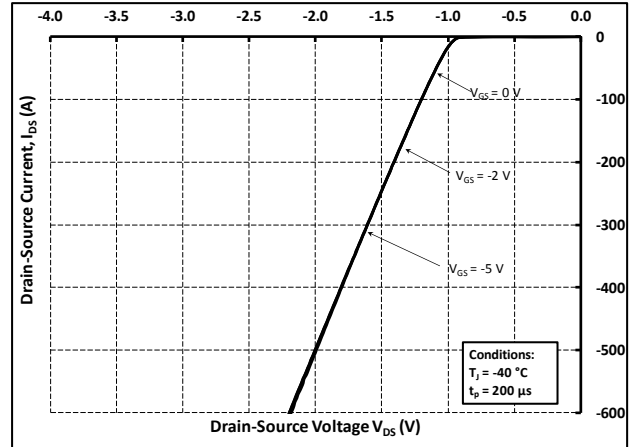


Fig 8. Typical Diode Behavior $T_J = -40$ $^{\circ}$ C

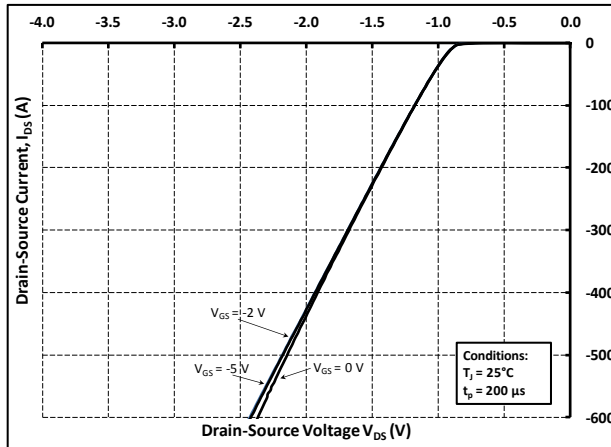


Fig 9. Typical Diode Behavior $T_J = 25$ $^{\circ}$ C

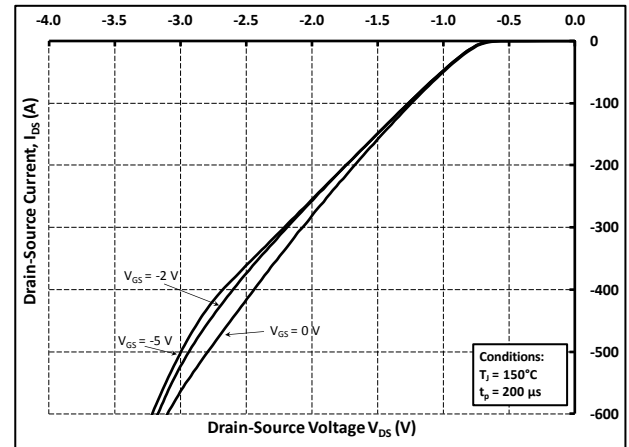


Fig 10. Typical Diode Behavior $T_J = 150$ $^{\circ}$ C

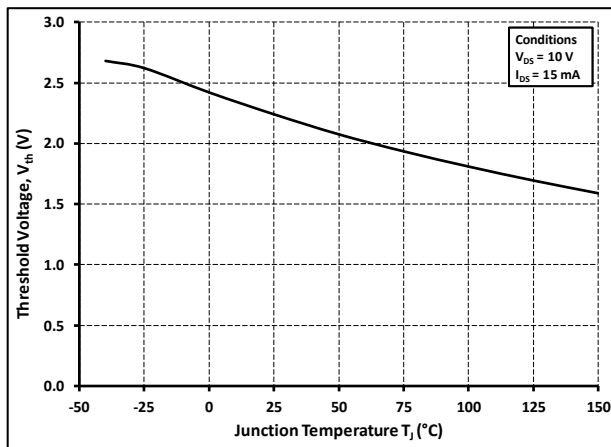


Fig 11. Typical Threshold Voltage vs. Temperature

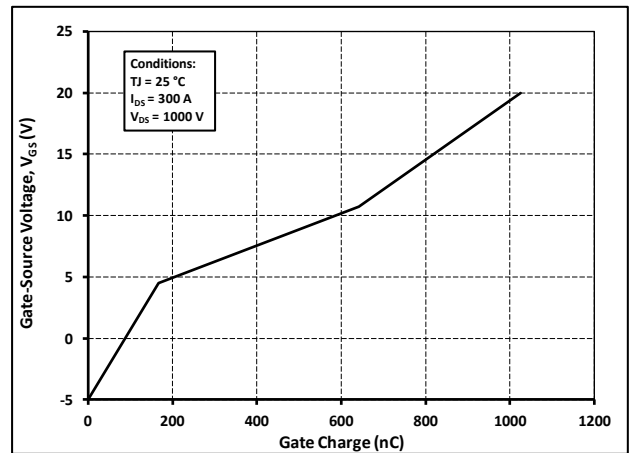


Fig 12. Typical Gate Charge



Typical Performance

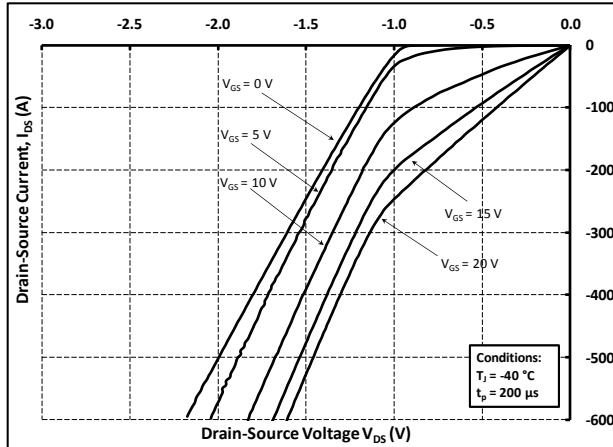


Fig 13. Typical 3rd Quadrant Behavior $T_j = -40\text{ }^{\circ}\text{C}$

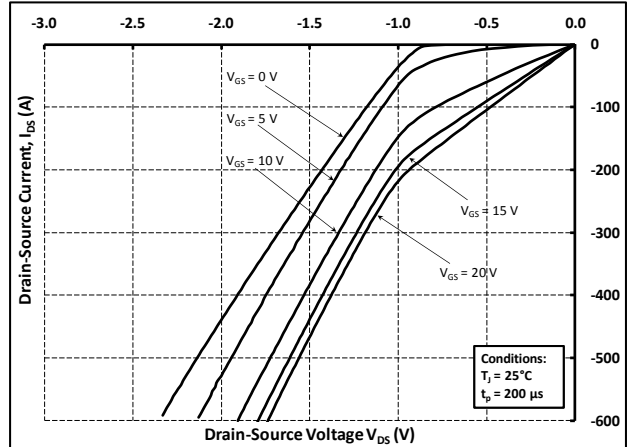


Fig 14. Typical 3rd Quadrant Behavior $T_j = 25\text{ }^{\circ}\text{C}$

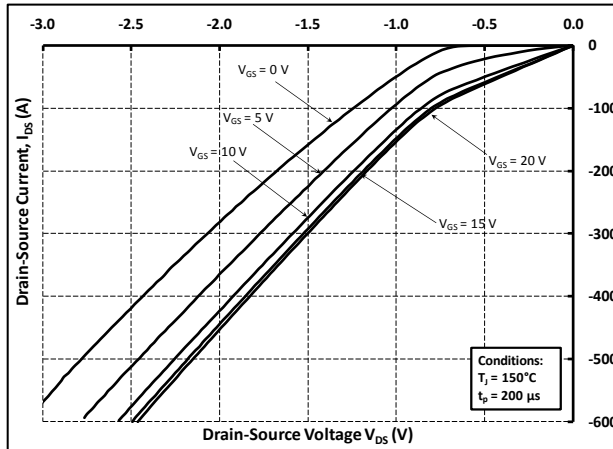


Fig 15. Typical 3rd Quadrant Behavior $T_j = 150\text{ }^{\circ}\text{C}$

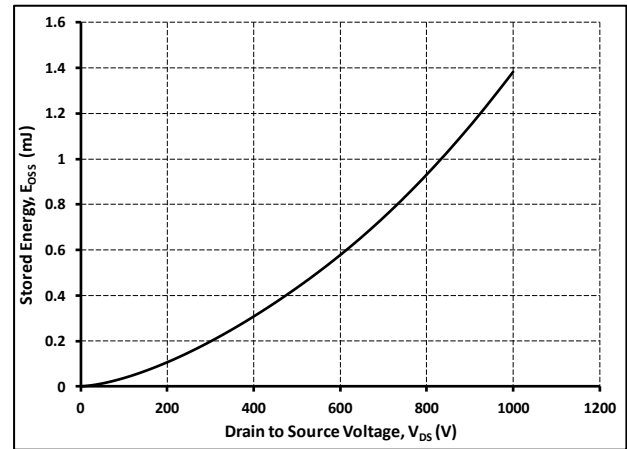


Fig 16. Typical Output Capacitor Stored Energy

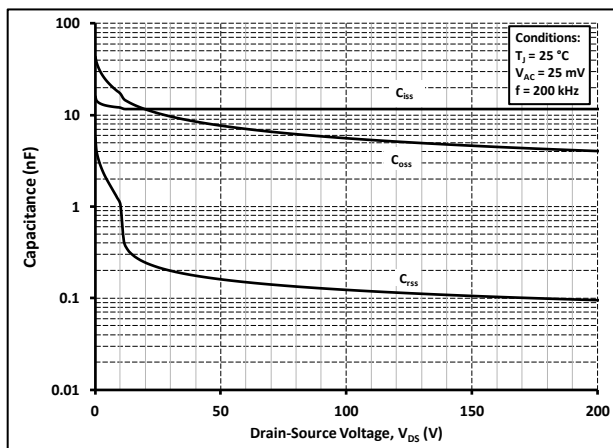


Fig 17. Typical Capacitances vs. Drain-Source Voltage. (0-200V)

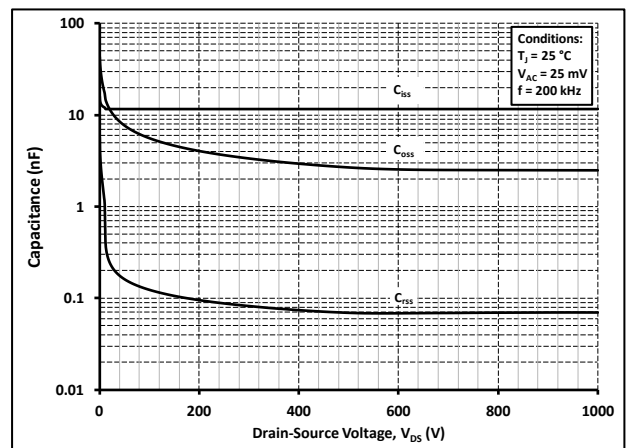


Fig 18. Typical Capacitances vs. Drain-Source Voltage. (0-1000V)



Typical Performance

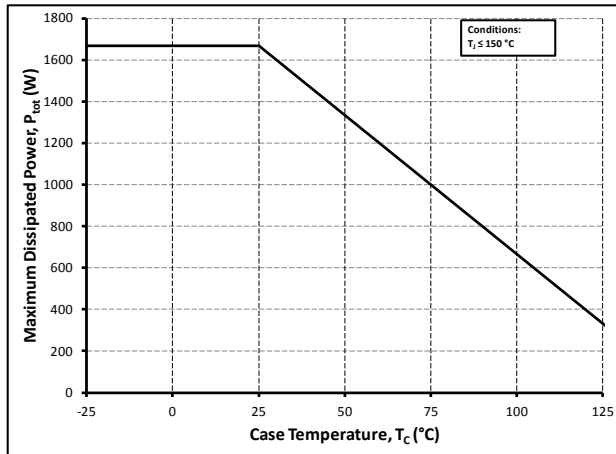


Fig 19. Max. Continuous Power Derating Curve vs. Case Temperature.

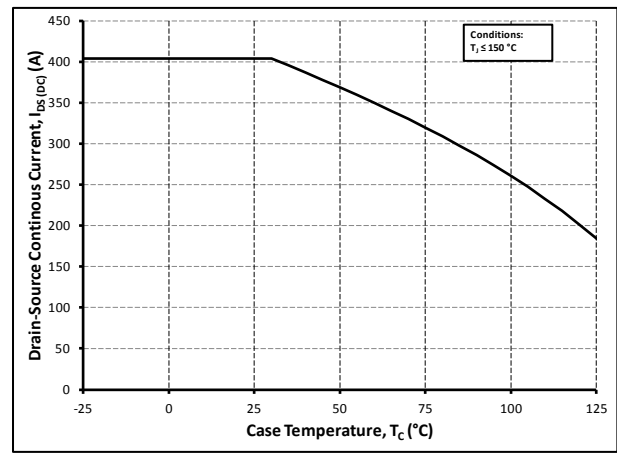


Fig 20. Max. Continuous Current Derating Curve vs. Case Temperature

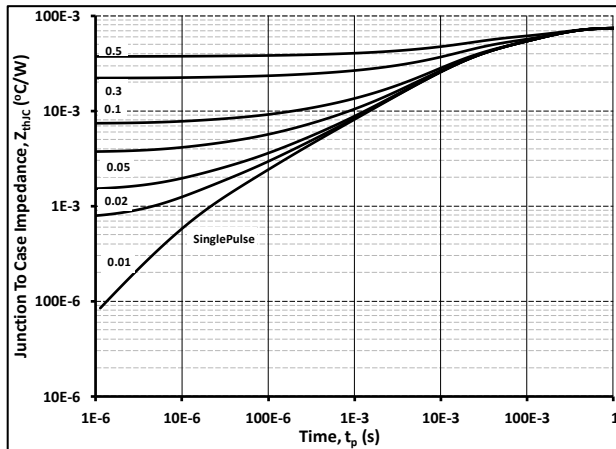


Fig 21. Typical Transient Thermal Impedance - MOSFET

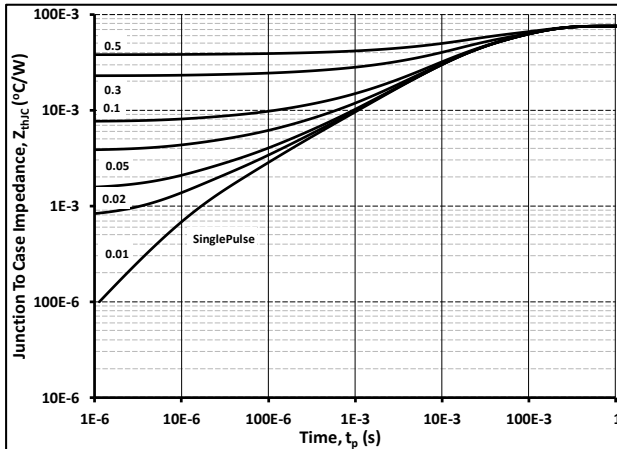


Fig 22. Typical Transient Thermal Impedance - DIODE

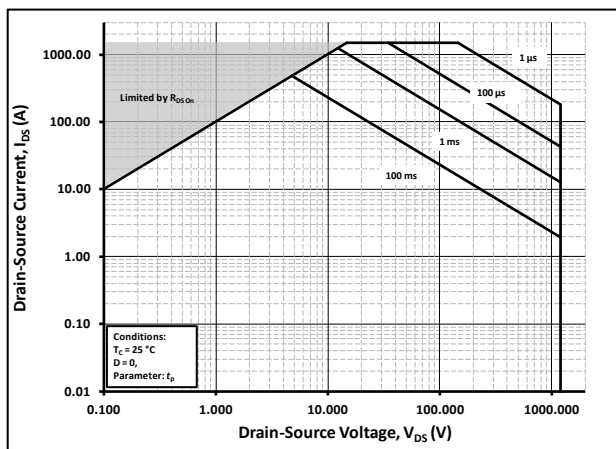


Fig 23. MOSFET Safe Operating Area

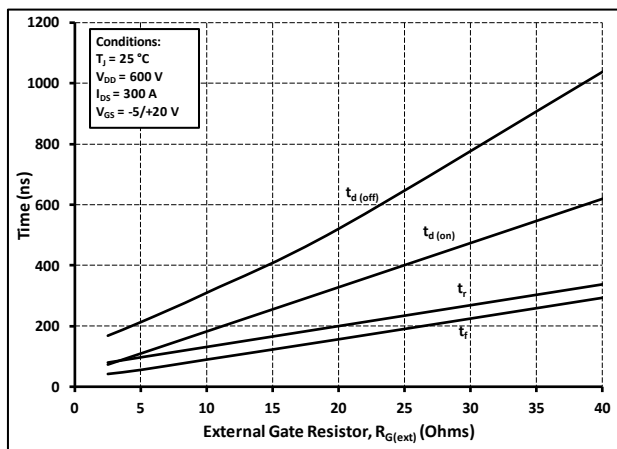


Fig 24. Typical Inductive Switching Time vs Gate Resistance ($V_{DD} = 600V$, $I_D = 300A$)

Typical Performance

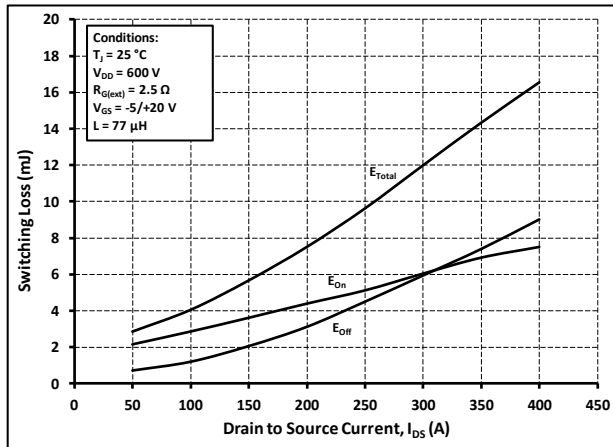


Fig 25. Typical Clamped Inductive Switching Energy vs Drain Current ($V_{DD} = 600\text{V}$)

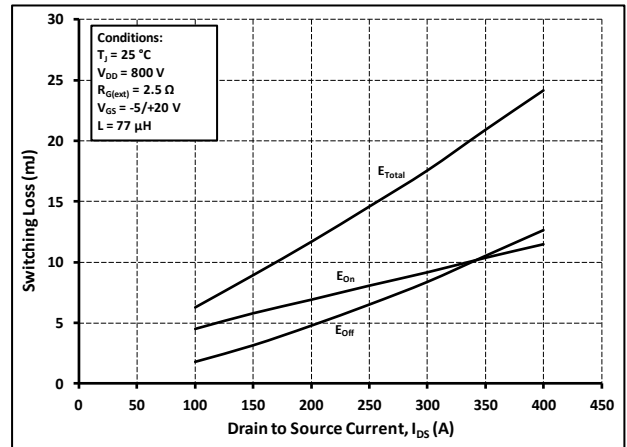


Fig 26. Typical Clamped Inductive Switching Energy vs Drain Current ($V_{DD} = 800\text{V}$)

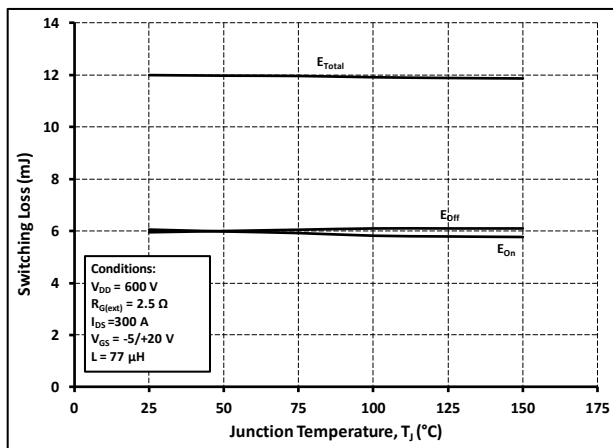


Fig 27. Typical Switching Loss vs. Temperature

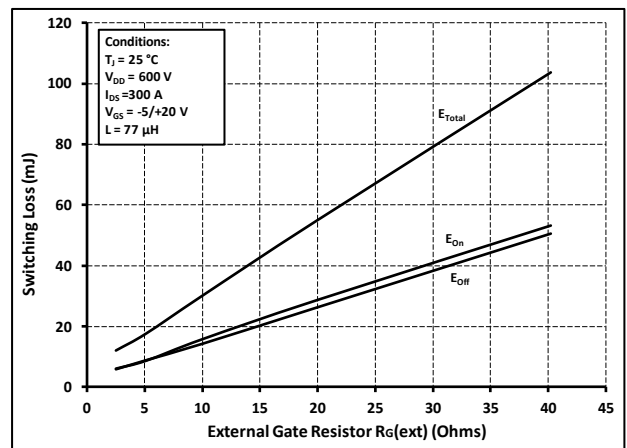
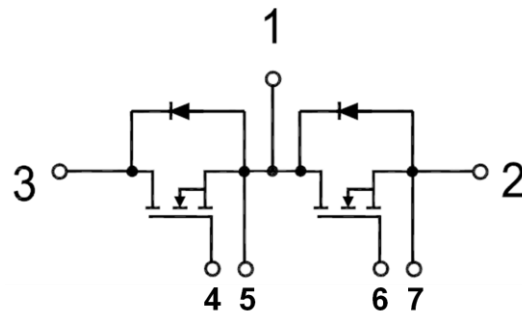


Fig 28. Typical Switching Loss vs. Gate Resistance

Schematic



Mechanical Characteristics (in mm)

